

<b>Issue Classification</b>				Application/Control No.		Applicant(s)/Patent under Reexamination	
				10/620,532		FARNHAM ET AL.	
				Examiner		Art Unit	
				Sean E. Aeder, Ph.D.		1642	

ISSUE CLASSIFICATION						
ORIGINAL		CROSS REFERENCE(S)				
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)			
530	350	424	185.1			
INTERNATIONAL CLASSIFICATION						
C	0	7	K	1/00		
A	6	1	K	39/00		
			/			
			/			
			/			
Sean E Aeder (Assistant Examiner) <i>Wb6660</i> (Date)				JEFFREY SIEW JEFFREY SIEW SUPERVISORY PATENT EXAMINER Jeffrey Siew <i>Jeffrey Siew</i> (Primary Examiner) <i>6/19/08</i> (Date)	Total Claims Allowed: 4	
Kim Downing (Legal Instruments Examiner) <i>Wb6660</i> (Date)				O.G. Print Claim(s) first	O.G. Print Fig. none	

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
Final	Original	Final	Original	Final	Original	Final	Original
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